PCN Number: 201			170828002A		PCN Date:		e:	May 3, 2019		
Title: Qualification of FF			of FFA	FAB as additional Fab site option for select devices						
Cu	stomer	Contact:		PCN Manager		Dept:			Quality Services	
Proposed 1 st Ship Date:			:	N/A Estimat Availab		•		le	Date provided at sample request.	
Ch	ange Ty	ype:								
Assembly Site			Assembly Process				Ass	Assembly Materials		
	Design			☐ Electrical Specification				Mechanical Specification		
	Test Site			Packing/Shipping/Labeling]		Tes	st Process	
	Wafer Bump Site			☐ Wafer Bump Material				Wa	afer Bump Process	
			Wafer Fab Materials				Wa	afer Fab Process		
					Part number chan	ge				
	PCN Details									
De	Description of Change:									
					·					

The purpose of Rev A is to cancel the addition of FFAB as an additional Fab source for select devices in the LBC7 Fab Process. Affected devices will remain in their current location.

Texas Instruments is pleased to announce the qualification of its FFAB fabrication facility as an additional Wafer Fab source for the selected devices listed in the "Product Affected" section.

С	urrent Fab Site	9	Additional Fab Site			
Current Fab Site	Process	Wafer Diameter	Additional Fab Site	Process	Wafer Diameter	
RFAB	LBC7	300 mm	<mark>FFAB</mark>	LBC7	200 mm	

Qual details are provided in the Qual Data Section.

Reason for Change:

Continuity of Supply

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

Current:

Current Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
RFAB	RFB	USA	Richardson

New Fab Site:

New Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
FR BIP 1	TID	DEU	Freising

Sample product shipping label (not actual product label)





(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T) LOT: 3959047MLA (4W) TKY(1T) 7523483\$I2 (P) (2P) REV: (20L) CSO: SHE (21L) CCO:USA (22L) ASO:MLA (23L) ACO: MYS

Product Affected:

SN1607003PWPR	TPA3136D2PWPR	TPA3137D2PWP	TPA3137D2PWPR	
---------------	---------------	--------------	---------------	--

Qualification Report

LBC7 G2PA3136D2A0 offload from RFAB to FFAB

Approve Date 02-Aug-2017

Product Attributes

Attributes	Qual Device: TPA3137D2PWP	QBS Process Reference: TCA6416PW
Assembly Site	TAI	MLA
Package Family	HTSSOP	TSSOP
Flammability Rating	UL 94 V-0	UL 94 V 0
Wafer Fab Supplier	FFAB	FFAB
Wafer Fab Process	LBC7	LBC7

⁻ QBS: Qual By Similarity

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: TPA3137D2PWP	QBS Process Reference: TCA6416PW
AC	Autoclave 121C	96 Hours	-	3/231/0
ED	Electrical Characterization	Per Datasheet Parameters	Pass	Pass
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0
HBM	ESD - HBM	4000 V	1/3/0	-
CDM	ESD - CDM	1500 V	1/3/0	1/3/0
HTOL	Life Test, 150C	300 Hours	-	3/231/0
HTSL	High Temp. Storage Bake, 150C	1000 Hours	-	3/231/0
LU	Latch-up	(per JESD78)	-	1/9/0
TC	Temperature Cycle, -65/150C	500 Cycles	-	3/231/0
WBP	Bond Pull	Wires	1/76/0	-
WBS	Ball Bond Shear	Wires	1/76/0	-

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
WW PCN Team	PCN_ww_admin_team@list.ti.com

⁻ Qual Device TPA3137D2PWP is qualified at LEVEL3-260C

⁻ Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

⁻ The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

⁻ The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles